

Am27C010

1 Megabit (131,072 x 8-Bit) CMOS EPROM

DISTINCTIVE CHARACTERISTICS

- **Fast access time**
 - 45 ns maximum access time
- **Low power consumption**
 - 20 μ A typical CMOS standby current
- **JEDEC-approved pinout**
- **Single +5 V power supply**
- **$\pm 10\%$ power supply tolerance available**
- **100% Flashrite™ programming**
 - Typical programming time of 16 seconds
- **Latch-up protected to 100 mA from -1 V to $V_{CC} + 1$ V**
- **High noise immunity**
- **Versatile features for simple interfacing**
 - Both CMOS and TTL input/output compatibility
 - Two line control functions
- **Compact 32-pin DIP, PDIP, TSOP, PLCC packages**

GENERAL DESCRIPTION

The Am27C010 is a 1 Megabit ultraviolet erasable programmable read-only memory. It is organized as 128K words by 8 bits per word, operates from a single +5 V supply, has a static standby mode, and features fast single address location programming. Products are available in windowed ceramic DIP packages as well as plastic one time programmable (OTP) PDIP, TSOP, and PLCC packages.

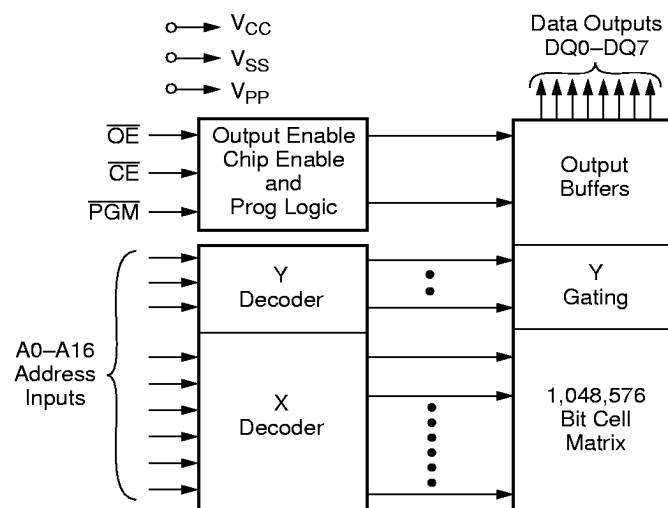
Typically, any byte can be accessed in less than 45 ns, allowing high-performance microprocessors to operate without wait states. The Am27C010 offers separate Output Enable (\overline{OE}) and Chip Enable (\overline{CE})

controls, thus eliminating bus contention in a multiple bus microprocessor system.

AMD's CMOS process technology provides high speed, low power, and high noise immunity. Typical power consumption is only 100 mW in active mode, and 100 μ W in standby mode.

All signals are TTL levels, including programming signals. Bit locations may be programmed singly, in blocks, or at random. The Am27C010 supports AMD's Flashrite programming algorithm (100 μ s pulses) resulting in a typical programming time of 16 seconds.

BLOCK DIAGRAM



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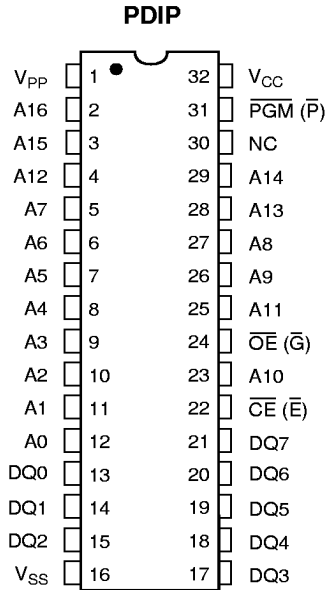
Publication# 10205 Rev: F Amendment/+2
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PRODUCT SELECTOR GUIDE

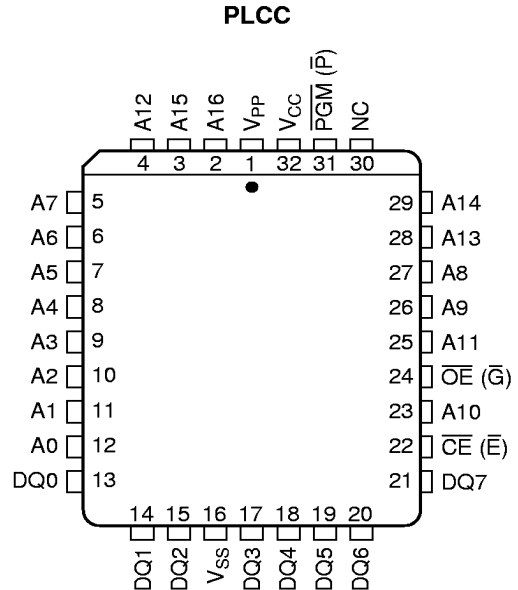
Family Part No:	Am27C010							
Ordering Part No: $V_{CC} = 5.0V \pm 5\%$ $V_{CC} = 5.0V \pm 10\%$	-45							-255
	-45	-55	-70	-90	-120	-150	-200	
Max Access Time (ns)	45	55	70	90	120	150	200	250
\overline{CE} (E) Access (ns)	45	55	70	90	120	150	200	250
\overline{OE} (G) Access (ns)	25	35	35	40	50	65	75	75

CONNECTION DIAGRAMS

Top View



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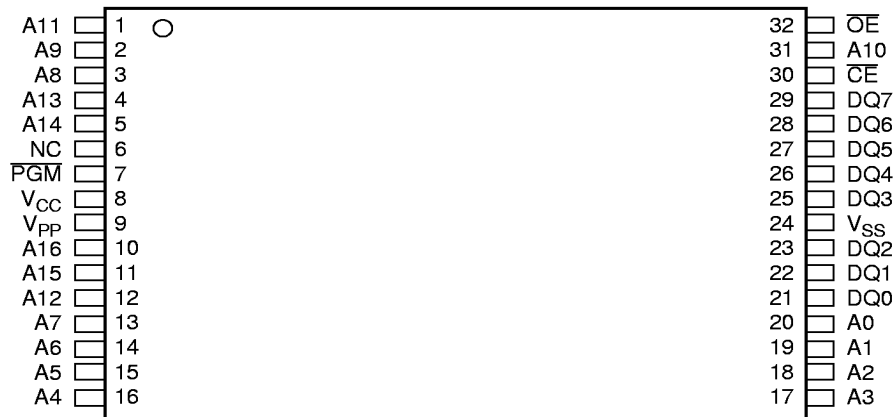


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Notes:

1. JEDEC nomenclature is in parenthesis.
2. The 32-pin DIP to 32-pin PLCC configuration varies from the JEDEC 28-pin DIP to 32-pin PLCC configuration.

TSOP



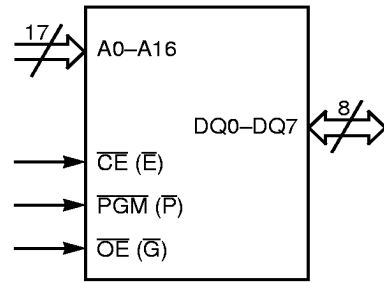
Standard Pinout

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PIN DESIGNATIONS

- A0–A16 = Address Inputs
- \overline{CE} (\overline{E}) = Chip Enable Input
- DQ0–DQ7 = Data Input/Outputs
- \overline{OE} (\overline{G}) = Output Enable Input
- \overline{PGM} (\overline{P}) = Program Enable Input
- V_{CC} = V_{CC} Supply Voltage
- V_{PP} = Program Voltage Input
- V_{SS} = Ground

LOGIC SYMBOL

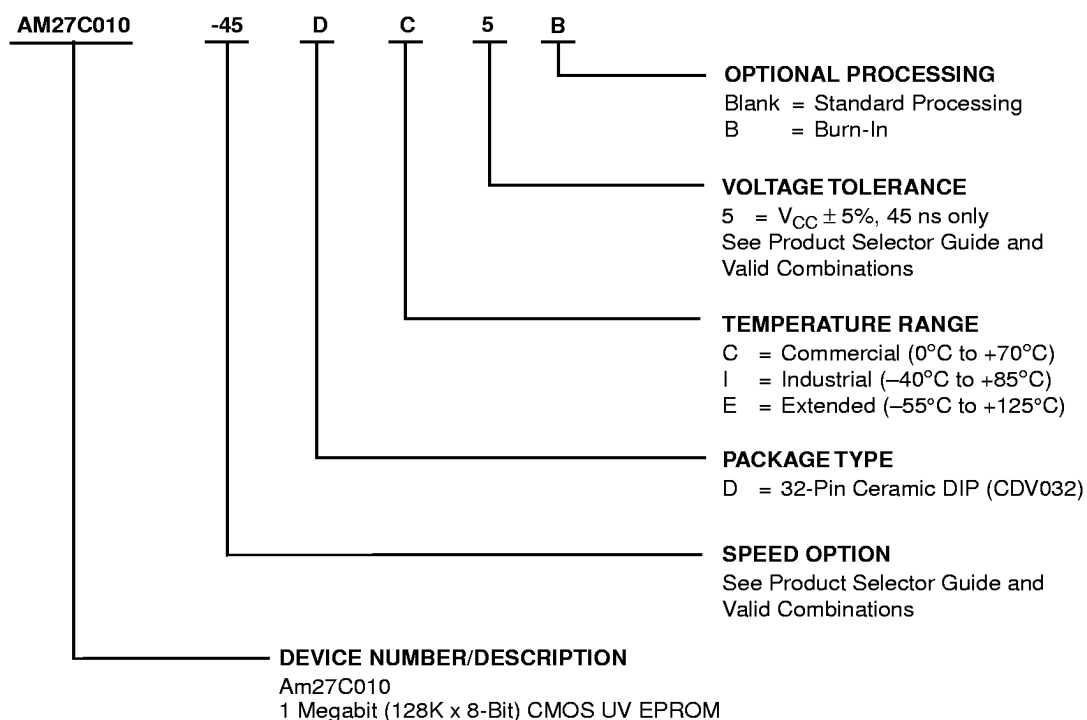


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ORDERING INFORMATION

UV EPROM Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:



Valid Combinations	
AM27C010-45 $V_{CC} = 5.0 \text{ V} \pm 5\%$	DC5, DC5B, DI5, DI5B
AM27C010-45 $V_{CC} = 5.0 \text{ V} \pm 10\%$	DC, DCB, DI, DIB
AM27C010-55	
AM27C010-70	
AM27C010-90	
AM27C010-120	DC, DCB, DE, DEB, DI, DIB
AM27C010-150	
AM27C010-200	
AM27C010-255 $V_{CC} = 5.0 \text{ V} \pm 5\%$	DC, DCB, DI, DIB

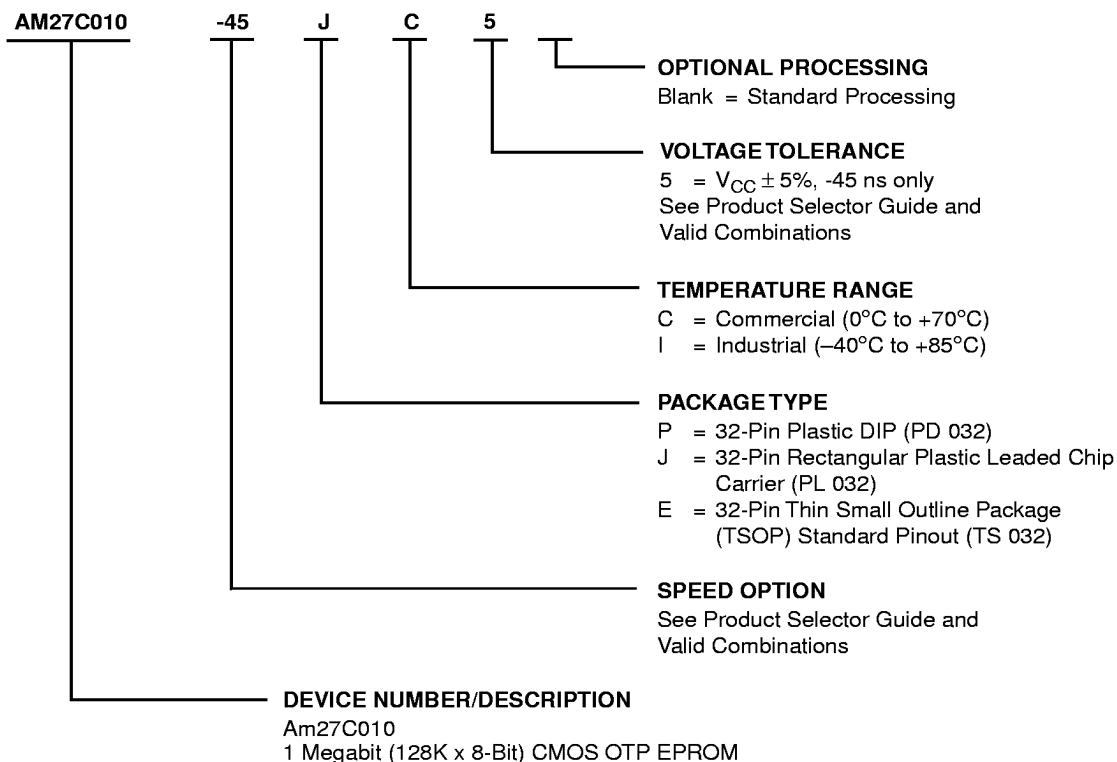
Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

ORDERING INFORMATION

OTP EPROM Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:



Valid Combinations	
AM27C010-45 $V_{CC} = 5.0\text{ V} \pm 5\%$	PC5, PI5, JC5, JI5, EC5, EI5
AM27C010-45 $V_{CC} = 5.0\text{ V} \pm 10\%$	PC, PI, JC, JI, EC, EI
AM27C010-55	
AM27C010-70	
AM27C010-90	
AM27C010-120	
AM27C010-150	
AM27C010-200	
AM27C010-255 $V_{CC} = 5.0\text{ V} \pm 5\%$	

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

FUNCTIONAL DESCRIPTION

Erasing the Am27C010

In order to clear all locations of their programmed contents, it is necessary to expose the Am27C010 to an ultraviolet light source. A dosage of 15 W seconds/cm² is required to completely erase an Am27C010. This dosage can be obtained by exposure to an ultraviolet lamp — wavelength of 2537 Å — with intensity of 12,000 μW/cm² for 15 to 20 minutes. The Am27C010 should be directly under and about one inch from the source and all filters should be removed from the UV light source prior to erasure.

It is important to note that the Am27C010, and similar devices, will erase with light sources having wavelengths shorter than 4000 Å. Although erasure times will be much longer than with UV sources at 2537 Å, exposure to fluorescent light and sunlight will eventually erase the Am27C010 and exposure to them should be prevented to realize maximum system reliability. If used in such an environment, the package window should be covered by an opaque label or substance.

Programming the Am27C010

Upon delivery, or after each erasure, the Am27C010 has all 1,048,576 bits in the “ONE”, or HIGH state. “ZEROS” are loaded into the Am27C010 through the procedure of programming.

The programming mode is entered when $12.75\text{ V} \pm 0.25\text{ V}$ is applied to the V_{PP} pin, \overline{CE} and \overline{PGM} are at V_{IL} and \overline{OE} is at V_{IH} .

For programming, the data to be programmed is applied 8 bits in parallel to the data output pins.

The Flashrite algorithm reduces programming time by using 100 μs programming pulse and by giving each address only as many pulses as are necessary in order to reliably program the data. After each pulse is applied to a given address, the data in that address is verified. If the data does not verify, additional pulses are given until it verifies or the maximum is reached. This process is repeated while sequencing through each address of the Am27C010. This part of the algorithm is done at $V_{CC} = 6.25\text{ V}$ to assure that each EPROM bit is programmed to a sufficiently high threshold voltage. After the final address is completed, the entire EPROM memory is verified at $V_{CC} = V_{PP} = 5.25\text{ V}$.

Please refer to Section 6 for programming flow chart and characteristics.

Program Inhibit

Programming of multiple Am27C010s in parallel with different data is also easily accomplished. Except for \overline{CE} , all like inputs of the parallel Am27C010 may be common. A TTL low-level program pulse applied to an

Am27C010 \overline{CE} input and $V_{PP} = 12.75\text{ V} \pm 0.25\text{ V}$, \overline{PGM} LOW, and \overline{OE} HIGH will program that Am27C010. A high-level \overline{CE} input inhibits the other Am27C020s from being programmed.

Program Verify

A verify should be performed on the programmed bits to determine that they were correctly programmed. The verify should be performed with \overline{OE} and \overline{CE} at V_{IL} , \overline{PGM} at V_{IH} , and V_{PP} between 12.5 V and 13.0 V.

Auto Select Mode

The auto select mode allows the reading out of a binary code from an EPROM that will identify its manufacturer and type. This mode is intended for use by programming equipment for the purpose of automatically matching the device to be programmed with its corresponding programming algorithm. This mode is functional in the $25^{\circ}\text{C} \pm 5^{\circ}\text{C}$ ambient temperature range that is required when programming the Am27C010.

To activate this mode, the programming equipment must force $12.0\text{ V} \pm 0.5\text{ V}$ on address line A9 of the Am27C010. Two identifier bytes may then be sequenced from the device outputs by toggling address line A0 from V_{IL} to V_{IH} . All other address lines must be held at V_{IL} during auto select mode.

Byte 0 ($A0 = V_{IL}$) represents the manufacturer code, and byte 1 ($A0 = V_{IH}$), the device identifier code. For the Am27C010, these two identifier bytes are given in the Mode Select Table. All identifiers for manufacturer and device codes will possess odd parity, with the MSB (DQ7) defined as the parity bit.

Read Mode

The Am27C010 has two control functions, both of which must be logically satisfied in order to obtain data at the outputs. Chip Enable (\overline{CE}) is the power control and should be used for device selection. Output Enable (\overline{OE}) is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that addresses are stable, address access time (t_{ACC}) is equal to the delay from \overline{CE} to output (t_{CE}). Data is available at the outputs t_{OE} after the falling edge of \overline{OE} , assuming that \overline{CE} has been LOW and addresses have been stable for at least $t_{ACC} - t_{OE}$.

Standby Mode

The Am27C010 has a CMOS standby mode which reduces the maximum V_{CC} current to 100 μA. It is placed in CMOS-standby when \overline{CE} is at $V_{CC} \pm 0.3\text{ V}$. The Am27C010 also has a TTL-standby mode which reduces the maximum V_{CC} current to 1.0 mA. It is placed in TTL-standby when \overline{CE} is at V_{IH} . When in standby mode, the outputs are in a high-impedance state, independent of the \overline{OE} input.

Output OR-Tieing

To accommodate multiple memory connections, a two-line control function is provided to allow for:

- Low memory power dissipation
 - Assurance that output bus contention will not occur
- It is recommended that \overline{CE} be decoded and used as the primary device-selecting function, while \overline{OE} be made a common connection to all devices in the array and connected to the READ line from the system control bus. This assures that all deselected memory devices are in their low-power standby mode and that the output pins are only active when data is desired from a particular memory device.

System Applications

During the switch between active and standby conditions, transient current peaks are produced on the rising and falling edges of Chip Enable. The magnitude of these transient current peaks is dependent on the output capacitance loading of the device. At a minimum, a 0.1 μF ceramic capacitor (high frequency, low inherent inductance) should be used on each device between V_{CC} and V_{SS} to minimize transient effects. In addition, to overcome the voltage drop caused by the inductive effects of the printed circuit board traces on EPROM arrays, a 4.7 μF bulk electrolytic capacitor should be used between V_{CC} and V_{SS} for each eight devices. The location of the capacitor should be close to where the power supply is connected to the array.

MODE SELECT TABLE

Mode		Pins	\overline{CE}	\overline{OE}	PGM	A0	A9	V_{PP}	Outputs
Read			V_{IL}	V_{IL}	X	X	X	X	D_{OUT}
Output Disable			X	V_{IH}	X	X	X	X	High-Z
Standby (TTL)			V_{IH}	X	X	X	X	X	High-Z
Standby (CMOS)			$V_{CC} \pm 0.3\text{ V}$	X	X	X	X	X	High-Z
Program			V_{IL}	V_{IH}	V_{IL}	X	X	V_{PP}	D_{IN}
Program Verify			V_{IL}	V_{IL}	V_{IH}	X	X	V_{PP}	D_{OUT}
Program Inhibit			V_{IH}	X	X	X	X	V_{PP}	High-Z
Auto Select (Note 3)	Manufacturer Code		V_{IL}	V_{IL}	X	V_{IL}	V_H	X	01H
	Device Code		V_{IL}	V_{IL}	X	V_{IH}	V_H	X	0E

Notes:

1. $V_H = 12.0\text{ V} \pm 0.5\text{ V}$.
2. X = Either V_{IH} or V_{IL} .
3. A1–A8 = A10–A16 = V_{IL} .
4. See DC Programming Characteristics for V_{PP} voltage during programming.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature

OTP Products -65°C to +125°C

All Other Products. -65°C to +150°C

Ambient Temperature

with Power Applied. -55°C to + 125°C

Voltage with Respect to V_{SS} All pins except A9, V_{PP} , V_{CC} . . -0.6 V to $V_{CC} + 0.5$ VA9 and V_{PP} (Note 2). -0.6 V to +13.5 V V_{CC} (Note 1). -0.6 V to +7.0 V**Notes:**

1. Minimum DC voltage on input or I/O pins is -0.5 V. During voltage transitions, inputs may overshoot V_{SS} to -2.0 V for periods of up to 20 ns. Maximum DC voltage on input and I/O pins is $V_{CC} + 0.5$ V. During voltage transitions, input and I/O pins may overshoot to $V_{CC} + 2.0$ V for periods up to 20 ns.
2. Minimum DC input voltage on A9 pin is -0.5 V. During voltage transitions, A9 and V_{PP} may overshoot V_{SS} to -2.0 V for periods of up to 20 ns. A9 and V_{CC} must not exceed +13.5 V at any time.

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure of the device to absolute maximum rating conditions for extended periods may affect device reliability.

OPERATING RANGES**Commercial (C) Devices**Ambient Temperature (T_A). 0°C to +70°C**Industrial (I) Devices**Ambient Temperature (T_A). -40°C to +85°C**Extended (E) Devices**Ambient Temperature (T_A). -55°C to +125°C**Supply Read Voltages** V_{CC} for Am27C010-45, 255 +4.75 V to +5.25 V V_{CC} for Am27C010-45, 55, 70,

90, 120, 150, 200 +4.50 V to +5.50 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

**DC CHARACTERISTICS over operating ranges unless otherwise specified
(Notes 1, 2, axnd 4)**

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
V _{OH}	Output HIGH Voltage	I _{OH} = -400 μA	2.4		V
V _{OL}	Output LOW Voltage	I _{OL} = 2.1 mA		0.45	V
V _{IH}	Input HIGH Voltage		2.0	V _{CC} + 0.5	V
V _{IL}	Input LOW Voltage		-0.5	+0.8	V
I _{LI}	Input Load Current	V _{IN} = 0 V to V _{CC}		1.0	μA
I _{LO}	Output Leakage Current	V _{OUT} = 0 V to V _{CC}		5.0	μA
I _{CC1}	V _{CC} Active Current (Note 3)	CE = V _{IL} , f = 10 MHz, I _{OUT} = 0 mA	C/I Devices	30	mA
			E Devices	60	
I _{CC2}	V _{CC} TTL Standby Current	CE = V _{IH}		1.0	mA
I _{CC3}	V _{CC} CMOS Standby Current	CE = V _{CC} ± 0.3 V		100	μA
I _{PP1}	V _{PP} Current During Reading	CE = OE = V _{IL} , V _{PP} = V _{CC}		100	μA

Notes:

- V_{CC} must be applied simultaneously or before V_{PP} and removed simultaneously or after V_{PP}
- Caution:** The Am27C010 must not be removed from (or inserted into) a socket when V_{CC} or V_{PP} is applied.
- I_{CC1} is tested with CE = V_{IH} to simulate open outputs.
- Minimum DC Input Voltage is -0.5 V. During transitions, the inputs may overshoot to -2.0 V for periods less than 20 ns. Maximum DC Voltage on output pins is V_{CC} + 0.5 V, which may overshoot to V_{CC} + 2.0 V for periods less than 20 ns.

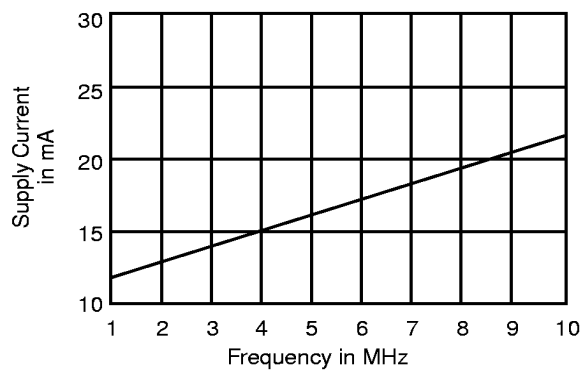


Figure 1. Typical Supply Current vs. Frequency
V_{CC} = 5.5 V, T = 25°C

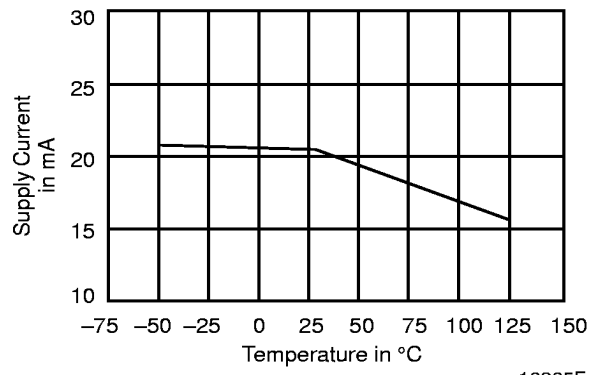


Figure 2. Typical Supply Current vs. Temperature
V_{CC} = 5.5 V, f = MHz

CAPACITANCE

Parameter Symbol	Parameter Description	Test Conditions	CDV032		PL 032		PD 032		TS 032		Unit
			Typ	Max	Typ	Max	Typ	Max	Typ	Max	
C_{IN}	Input Capacitance	$V_{IN} = 0$	9	12	8	12	8	12	10	12	pF
C_{OUT}	Output Capacitance	$V_{OUT} = 0$	13	15	11	14	11	14	12	14	pF

Notes:

1. This parameter is only sampled and not 100% tested.
2. $T_A = +25^\circ\text{C}$, $f = 1\text{ MHz}$.

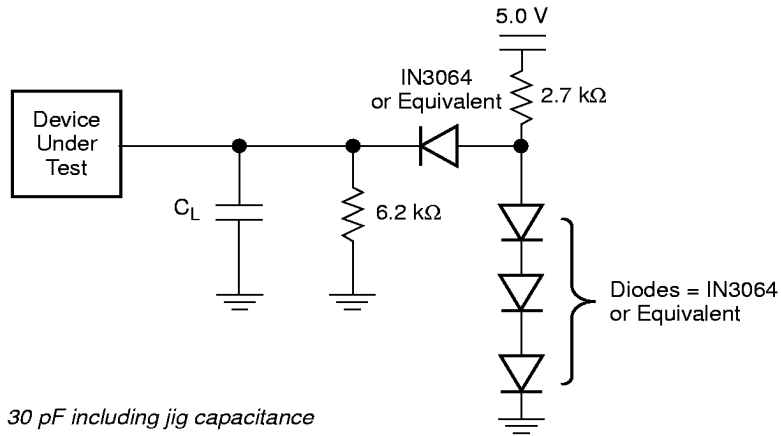
AC CHARACTERISTICS

Parameter Symbols		Parameter Description	Test Conditions	Am27C010									Unit
JEDEC	Standard			-45	-55	-70	-90	-120	-150	-200	-255		
t_{AVQV}	t_{ACC}	Address to Output Delay	\overline{CE} , $\overline{OE} = V_{IL}$	Max	45	55	70	90	120	150	200	250	ns
t_{ELQV}	t_{CE}	Chip Enable to Output Delay	$\overline{OE} = V_{IL}$	Max	45	55	70	90	120	150	200	250	ns
t_{GLQV}	t_{OE}	Output Enable to Output Delay	$\overline{CE} = V_{IL}$	Max	25	35	35	40	50	65	75	75	ns
t_{EHQZ} t_{GHQZ}	t_{DF} (Note 3)	Chip Enable High or Output Enable High to Output Float, Whichever Occurs First		Max	25	25	25	25	35	35	40	40	ns
t_{AXQX}	t_{OH}	Output Hold from Addresses, \overline{CE} , or \overline{OE} , Whichever Occurs First		Min	0	0	0	0	0	0	0	0	ns

Notes:

1. **Caution:** Do not remove the Am27C010 from (or insert it into) a socket or board that has V_{PP} or V_{CC} applied.
2. V_{CC} must be applied simultaneously or before V_{PP} and removed simultaneously or after V_{PP} .
3. This parameter is sampled and not 100% tested.
4. Switching characteristics are over operating range, unless otherwise specified.
5. Test Conditions for Am27C010-45 and -55:
 Output Load: 1 TTL gate and $C_L = 30\text{ pF}$
 Input rise and fall times: 20 ns
 Input pulse levels: 0.0 V to 3.0 V
 Timing measurement reference level Inputs and Outputs: 1.5 V
 Test Conditions for all others:
 Output Load: 1 TTL gate and $C_L = 100\text{ pF}$
 Input rise and fall times: 20 ns
 Input pulse levels: 0.45 V to 2.4 V
 Timing measurement reference level Inputs and Outputs: 0.8 and 2.0 V

SWITCHING TEST CIRCUIT

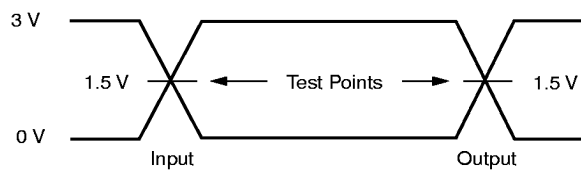


Notes:
 For -45 and -55: $C_L = 30 \text{ pF}$ including jig capacitance
 For all others: $C_L = 100 \text{ pF}$ including jig capacitance

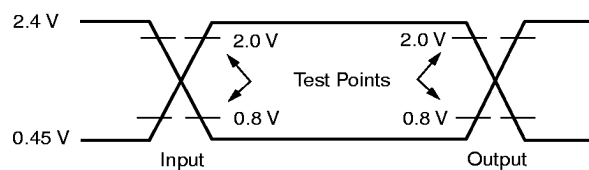
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Figure 1. Test Conditions

SWITCHING TEST WAVEFORM



AC Testing for -45 and -55 devices: Inputs are driven at 3.0 V for a logic "1" and 0 V for a logic "0". Input pulse rise and fall times are $\leq 20 \text{ ns}$.



AC Testing (except for -45 and -55 devices): Inputs are driven at 2.4 V for a logic "1" and 0.45 V for a logic "0". Input pulse rise and fall times are $\leq 20 \text{ ns}$.

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REVISION SUMMARY FOR AM27C010**Distinctive Characteristics:**

The fastest speed grade available is now 45 ns.

Product Selector Guide:

Added 45 ns column.

The V_{CC} operating range for the 55 ns speed grade changed from $\pm 5\%$ to $\pm 10\%$. The part number designation remains the same (-55).

Ordering Information, UV EPROM Products:

The 45 ns part number is now listed in the example. The nomenclature now has a method of clearly designating the voltage operating range and speed grade.

Valid Combinations: The 45 ns and 55 ns speed grades are now also available in the industrial temperature range and can be burned in.

Ordering Information, OTP EPROM Products:

Changed the part number example from -55 to -45. The nomenclature now has a method of clearly designating the voltage operating range and speed grade.

Valid Combinations: Added the 45 ns and 55 ns speed grades to the table.

Operating Ranges:

Changed Supply Read Voltages listings to match those in the Product Selector Guide.

AC Characteristics:

Added column for 45 ns speed grade, rearranged notes, moved text from table title to Note 4, renamed table.

Switching Test Circuit:

Added 45 ns to the C_L note on 30 pF test condition.

Switching Test Waveform:

Added the 3 V test waveform.

Introduction:

This amendment will be available through the Web in addition to, not instead of, the literature ordering hotline.

Switching Test Waveform:

The caption now reads "... Inputs are driven at ... 0 V for a logic "0" ...".

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